

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.

[illegible]

Examiner Signature	/Nashmiya Fayyaz/ (10/19/2006)	Date Considered	10/19/2006
-----------------------	--------------------------------	--------------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not

1 Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.

INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)

R.303674

Application Number

10/526307

Applicant(s)

Norbert BREUER

BT01

PC1/PTC

02 MAR 2005

Filing Date

Group Art Unit

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
dup		6,269,684 B1	08-07-2001	VOIGT E. MAKI, Jr., et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2003/0132146 A1	07-17-2003	Dettl GNEUSS			
NF		2004/0237654 A1	12-02-2004	Vincent SAVALL et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		GB 2 017 916 A	10-10-1979	United Kingdom				
		WO 01/43847 A2	06-21-2001	World IPO				
		WO 03/013707 A1	02-20-2003	World IPO				

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

		Takahashi K et al: "Measurement of Cake Thickness on Membrane for Microfiltration of Yeast Using Ultrasonic Polymer Concave Transducer" Journal of Chemical Engineering of Japan, JP, Bd. 224, Nr. 5, 01.10.1991, Seiten 599-603, XP000241639

EXAMINER	/Nashmiya Fayyaz/ (10/19/2006)	DATE CONSIDERED	10/19/2006
----------	--------------------------------	-----------------	------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.